Supplementary Material

Enhanced piezoelectric property in quenched BiFeO₃-based

piezoceramics: role of defects and mesophase

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Fig. S1 Sintering schedule of different heat treatments: (a) the normal sintered schedule, samples were sintered at 1100 °C for 2 h, and then cooled down with the furnace; (b) the quenching process schedule, samples were sintered at 1100 °C for 2 h, and then removed out of the furnace after sintering process and rapidly cooled down in the air.

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Fig. S2 *In-situ* measurement of the d_{33} as a function of temperature for FS and QS samples.



Fig. S3 Frequency dependence of AC conductivity for (a) FS sample selected according to Ref.¹ and (b) QS ceramic at different temperature points between 300 °C and 400 °C.



Fig. S4 The SEM micrographs of (a) FS and (b) QS samples.



Fig. S5 *P-E* hysteresis loops of FS amd QS samples, measured at 1 Hz.

Samples	Space - group	Lattice parameters			Phase	Refined factors		
		a (Å)	b (Å)	c (Å)	fraction (%)	R _{wp} (%)	R _p (%)	χ^2
FS	P4mm	3.9621	3.9621	4.1169	89.90	5.62	4.00	2.80
	R3mr	4.0310	4.0310	4.0310	10.10			
QS	P4mm	3.9606	3.9606	4.1193	87.61	4.28	2.82	3.70
	R3mr	4.0269	4.0269	4.0269	11.94			
	FeBi ₅ Ti ₃ O ₁₅	5.4665	5.4335	41.0241	0.45			

Table S1 Rietveld refinement parameters of FS and QS ceramics.

References

1. H. Zhao, Y. Hou, X. Yu, M. Zheng and M. Zhu, *J. Appl. Phys.*, 2018, **124**, 194103.